

IR Detectors based on n-i-p-i Superlattices

P. Paul Ruden

Department of Electrical Engineering
University of Minnesota
Minneapolis, Minnesota 55455

It has been demonstrated that the internal electric fields present in n-i-p-i doped semiconductor superlattices give rise to interband photo absorption well below the bandgap of the host semiconductor material. In addition, the internal fields separate the photo generated electrons and holes resulting in large non-equilibrium charge carrier lifetimes and, consequently, in large photoconductive gain. Experimental results on GaAs n-i-p-i superlattices have confirmed these expectations for photon wavelengths in the near infrared ($\lambda < 1.5 \mu\text{m}$). For an extension of the wavelength range to the mid and far infrared, semiconductors with smaller bandgaps are more suitable than GaAs as n-i-p-i superlattice host materials. Strong candidate materials are InAs and InSb because of their favorable growth and doping properties.

In this paper the principles of operation of n-i-p-i photodetectors will be discussed. Special consideration is given to issues that are relevant to the performance of IR detectors such as noise, dark current, and surface effects. In addition, we will discuss a novel IR detector that promises to provide information about the spectral distribution of the infrared radiation emitted from an object and, consequently, about its temperature, independent of the distance between detector and object. This detector makes use of the possibility to modulate the internal electric fields of an n-i-p-i superlattice with an applied voltage. By this technique the spectral responsivity of the detector may be controlled electrically and some information about the shape of the emission spectrum may be obtained.

IR DETECTORS BASED ON DOPING SUPERLATTICES

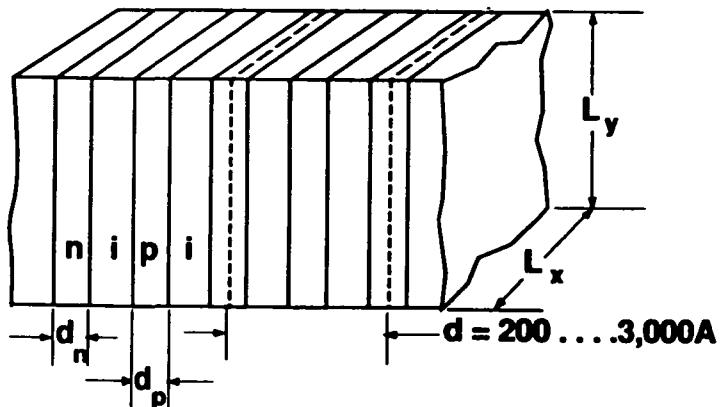
P. Paul Ruden

University of Minnesota
Department of Electrical Engineering

Outline

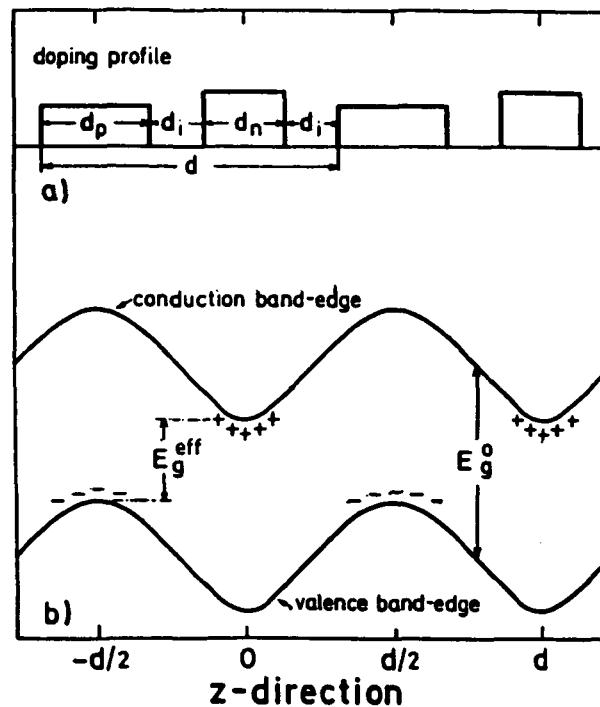
- Introduction, optical absorption in nipi SL
- Electroabsorption GaAs, InAs, InSb
- Noise in nipi detectors
- Spectrally agile detector
- Inhomogeneous excitation and surface effects
- Summary

Doping Superlattice (n-i-p-i)

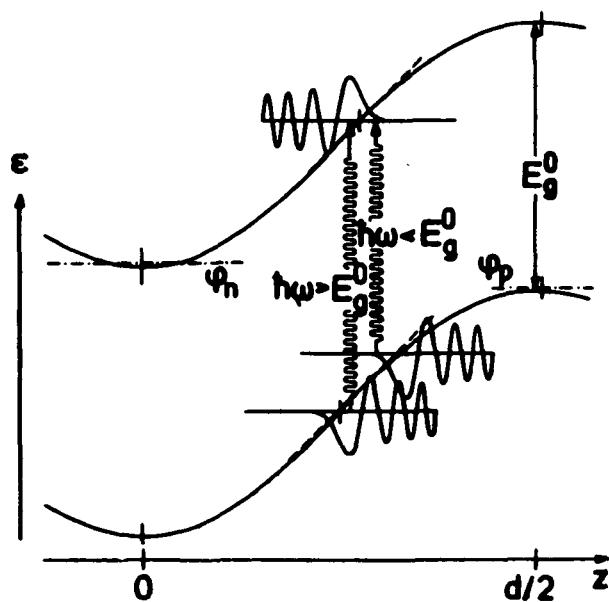


Materials: GaAs, AlGaAs, InP, GaP, InAs, InSb, InGaAs, PbTe, Si,...?

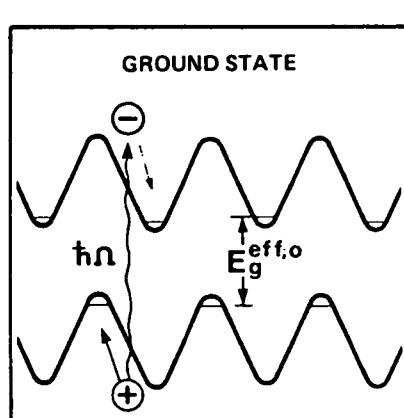
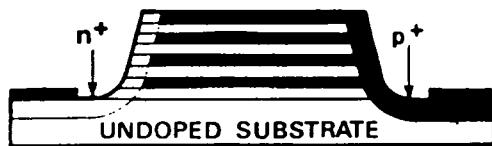
Schematic Doping Profile and Band Diagram of NIPI Superlattice



Photon Absorption in Doping Superlattice



DOPING SUPERLATTICE PHOTODETECTOR



Two modes of operation:

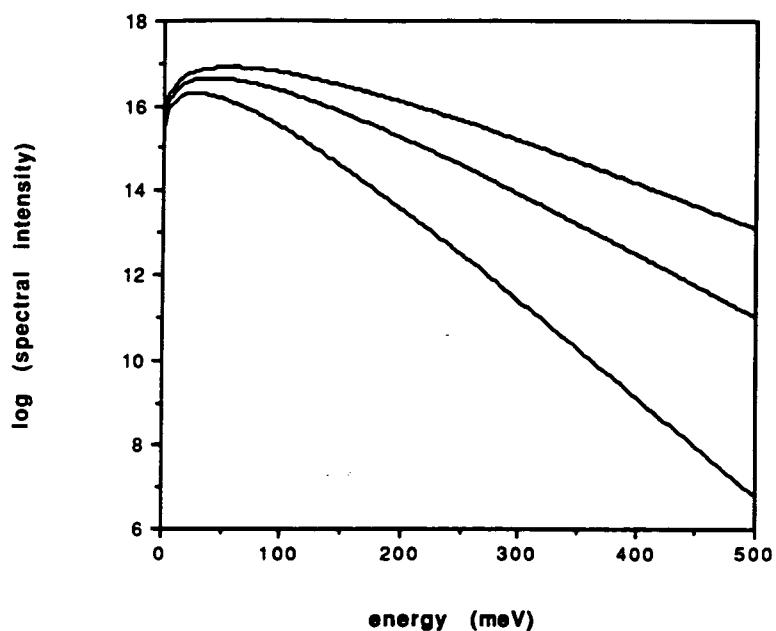
1) Photovoltaic mode:

$$\delta I_{np}$$

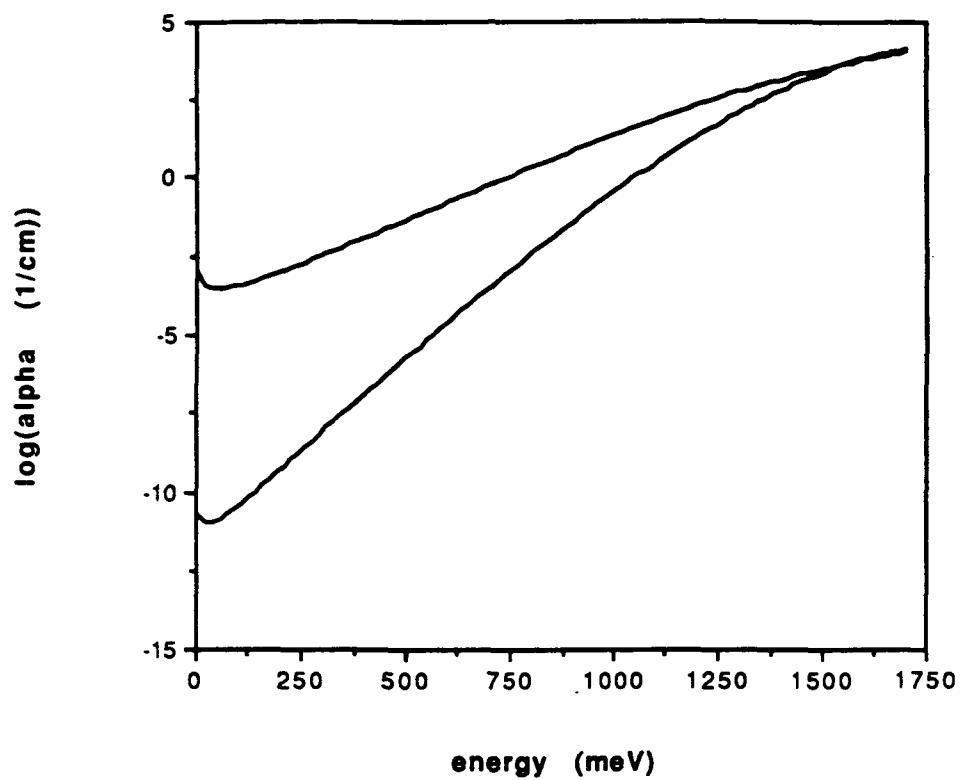
2) Photoconductive mode:

$$\delta I_{nn} \text{ or } \delta I_{pp}$$

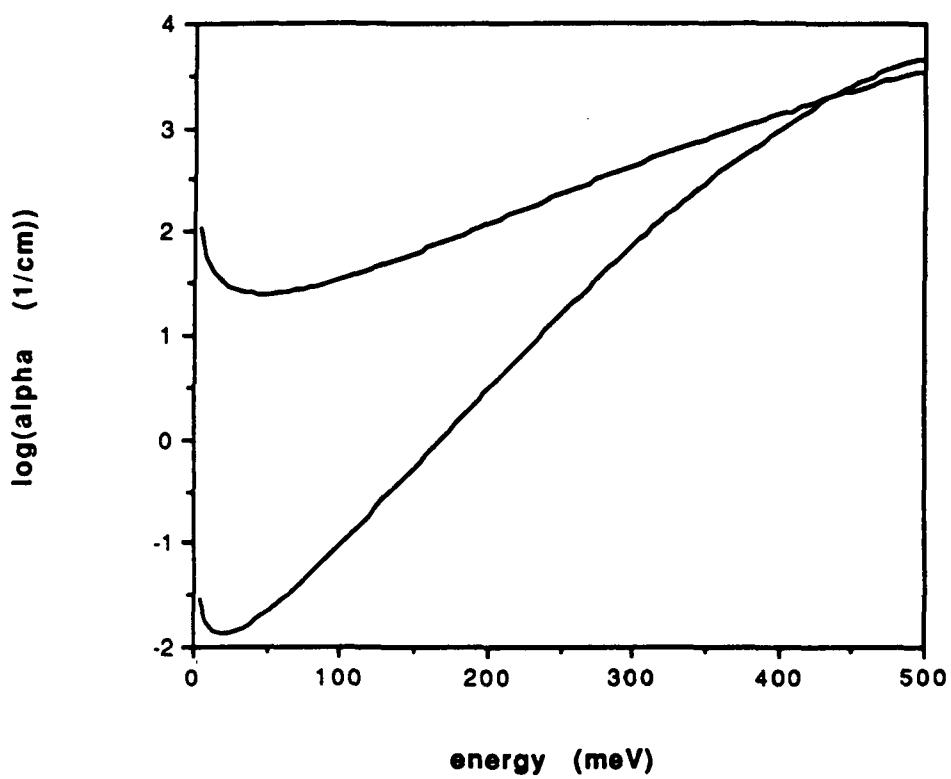
Blackbody spectra T=200K,300K,400K



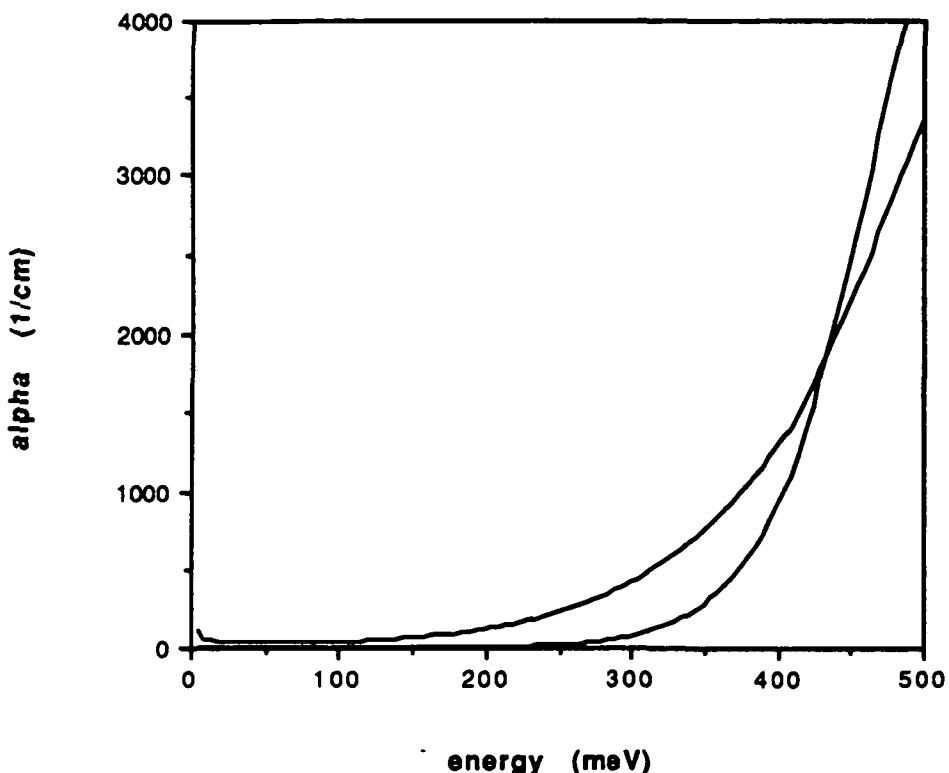
GaAs El. Abs. T=77K



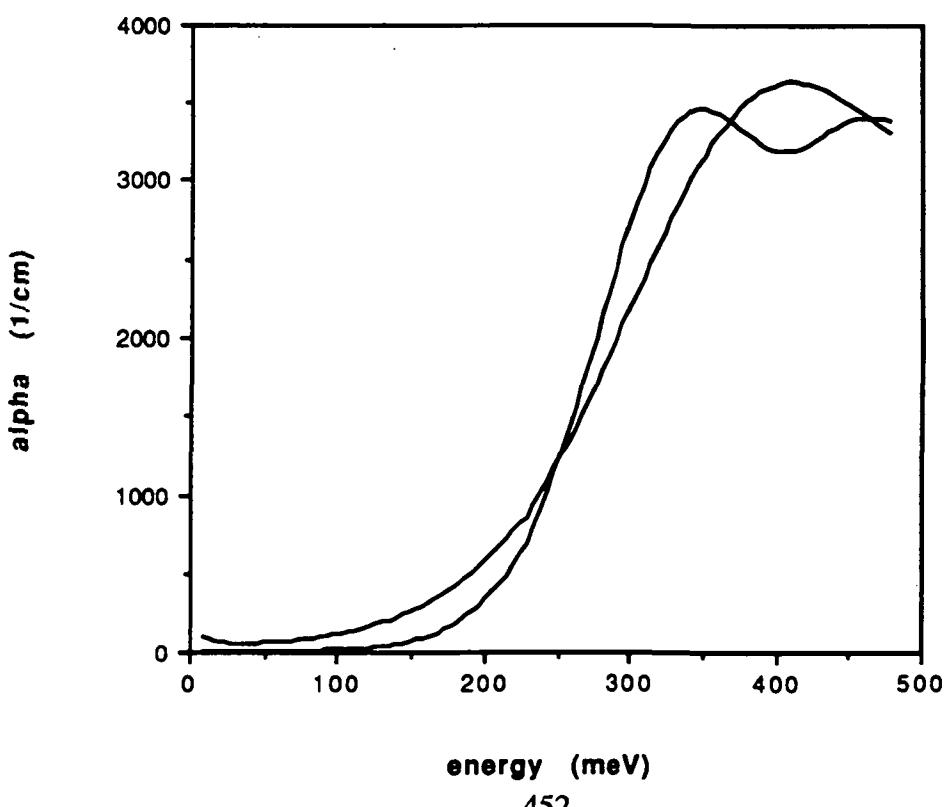
InAs El. Abs.



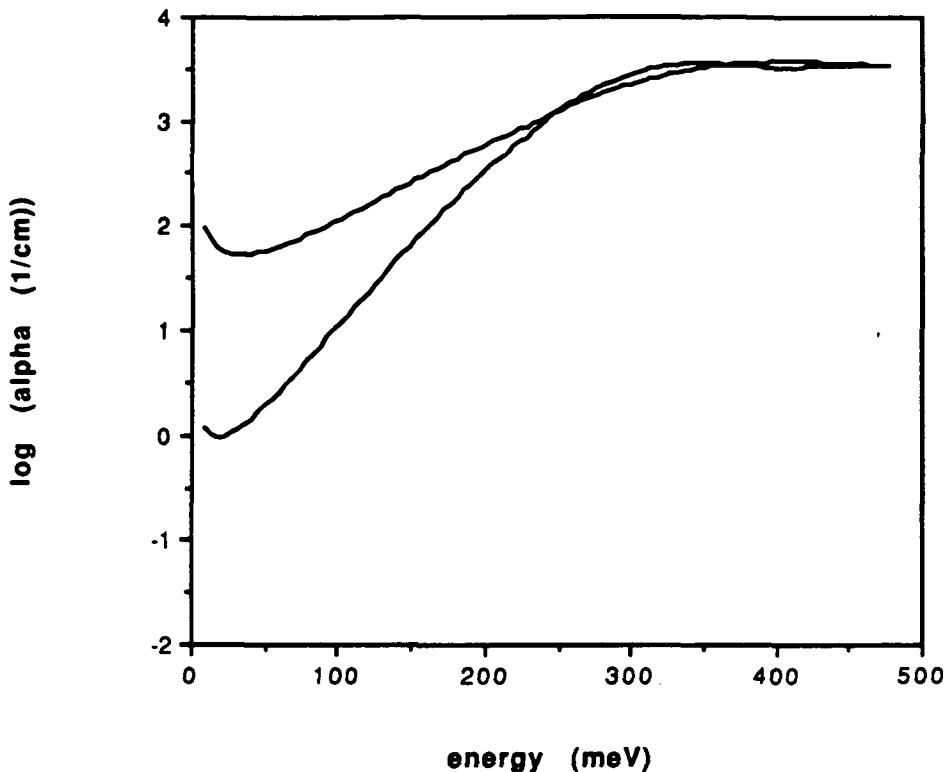
InAs El. Abs.



InSb El. Abs. T=77K



InSb El. Abs. T=77K



Example

InSb nipi BLIP

$$n_D^{(2)} = 3.5 \times 10^{12} \text{ cm}^{-2}$$

$$d_i = 100 \text{ \AA}$$

$$\rightarrow F_{bi} d_i \sim E_g^0$$

$$\hbar\omega_0 = 108 \text{ meV} \triangleq \lambda_0 = 11.5 \mu\text{m} \quad , \quad T_B = 300\text{K}$$

$$\alpha(\hbar\omega_0) = 130 \text{ cm}^{-1}$$

$$\bar{\alpha} = 51 \text{ cm}^{-1} \text{ with cut-off } \hbar\omega_c = 100 \text{ meV} \quad D^* = 2.6 \times 10^8 \sqrt{N_{SL}} \text{ cm} \sqrt{\text{Hz}} / \text{W}$$

$$\bar{\alpha} = 107 \text{ cm}^{-1} \text{ without cut-off} \quad D^* = 1.8 \times 10^8 \sqrt{N_{SL}} \text{ cm} \sqrt{\text{Hz}} / \text{W}$$

$$N_{SL} = 1750 \rightarrow D^* = 1.1 \times 10^{10} \text{ cm} \sqrt{\text{Hz}} / \text{W}$$

$$\text{compared to BLIP with } \eta = 1 \lambda_c = 11 \mu\text{m} \quad D^* = 3.4 \times 10^{10} \text{ cm} \sqrt{\text{Hz}} / \text{W}$$

Noise Sources in nipi IR Detectors

Detectivity

$$D^* = \sqrt{A} \frac{R}{I_{\text{noise}}} \sqrt{\Delta f}$$

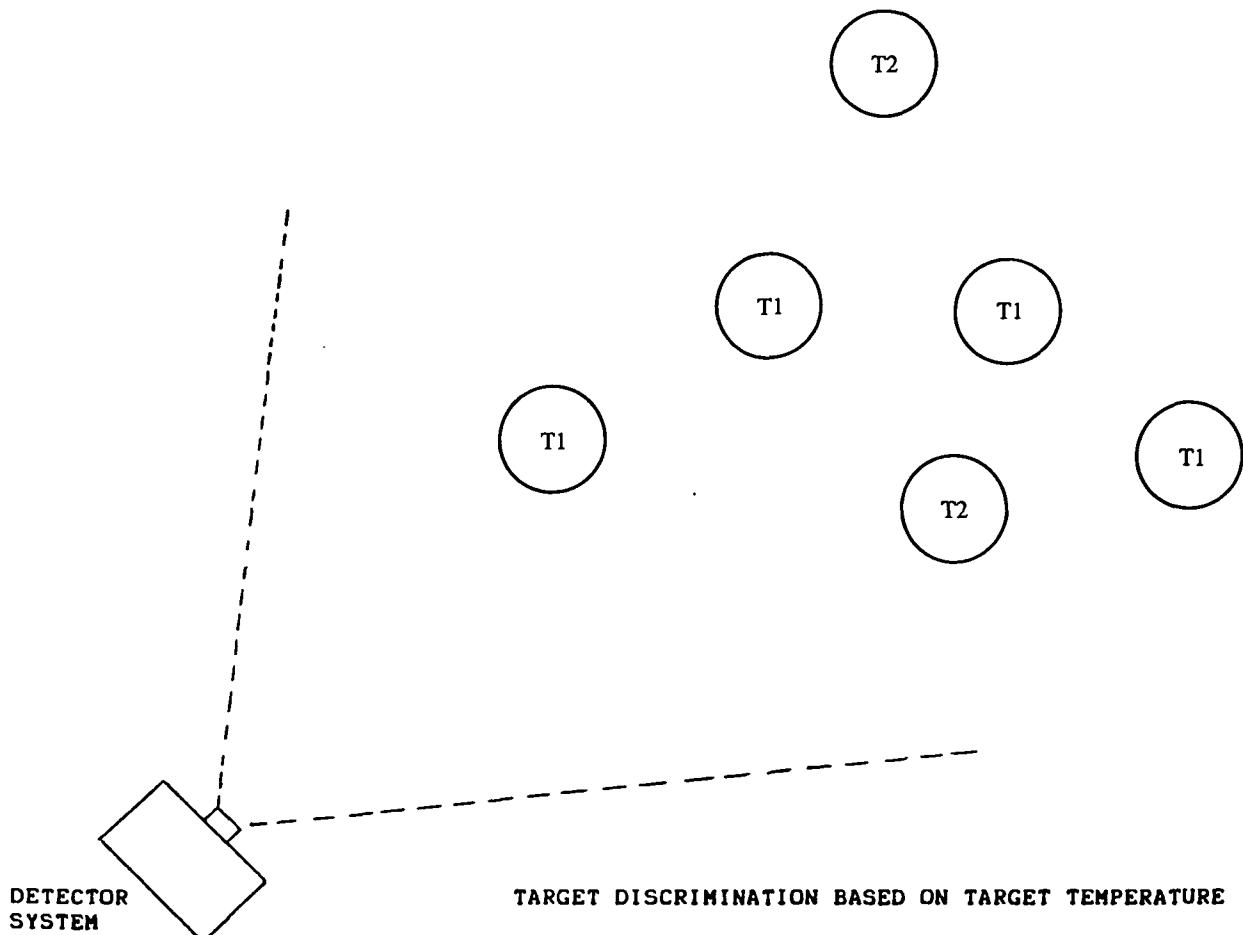
Thermal g-r noise limited : $D^* = \frac{1}{2h\omega} \frac{\alpha(\omega)d_i}{\sqrt{p(2)}} \sqrt{\tau} \sqrt{N_{\text{SL}}}$

$$\bar{\alpha} d_i \sigma_p T_B^3 < p(2)/\tau$$

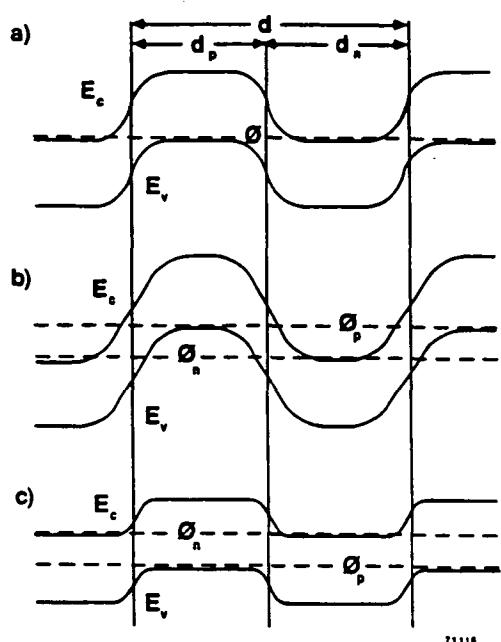
Background g-r noise limited : $D^* = \frac{1}{2h\omega} \frac{\alpha(\omega)}{(\bar{\alpha} \sigma_p T_B^3)^{1/2}} \sqrt{d_i} \sqrt{N_{\text{SL}}}$

$$\bar{\alpha} d_i \sigma_p T_B^3 > p(2)/\tau$$

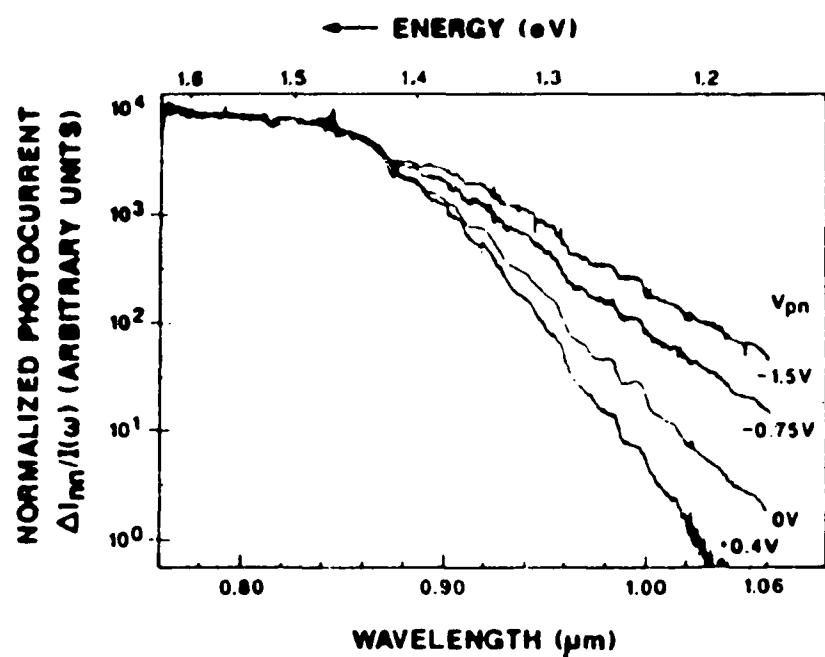
$$\bar{\alpha} = \frac{\int dE \alpha(E) M_p(E, T_B)}{\sigma_p T_B^3}$$



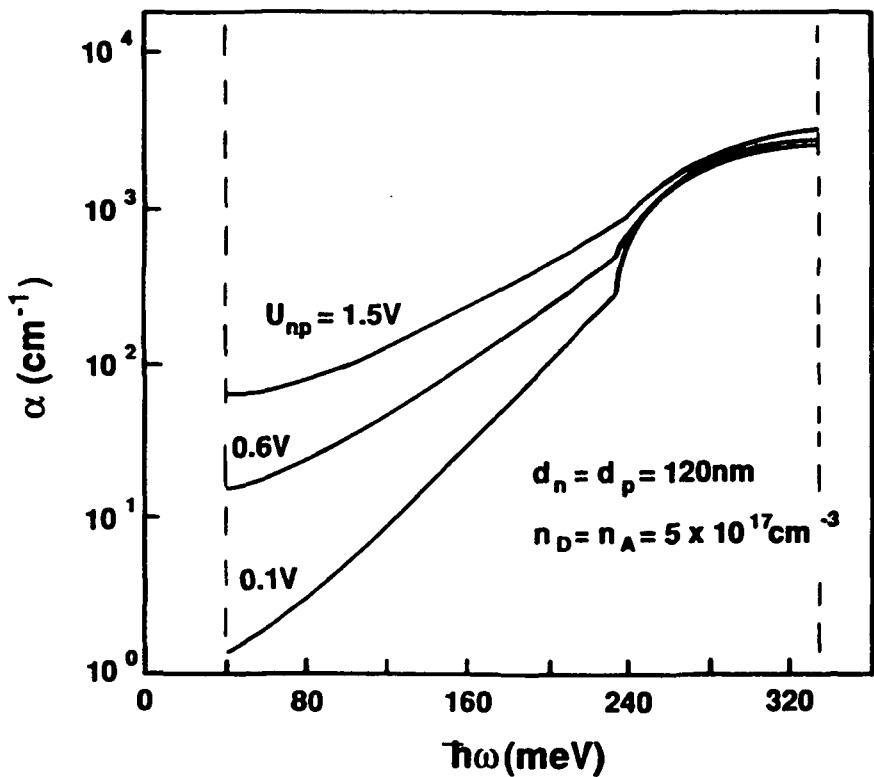
BANDPROFILE OF n-i-p-i CRYSTAL



- a) Ground State
- b) Reverse Bias U_{np}
- c) Forward Bias U_{np}



InSb DSL



70832

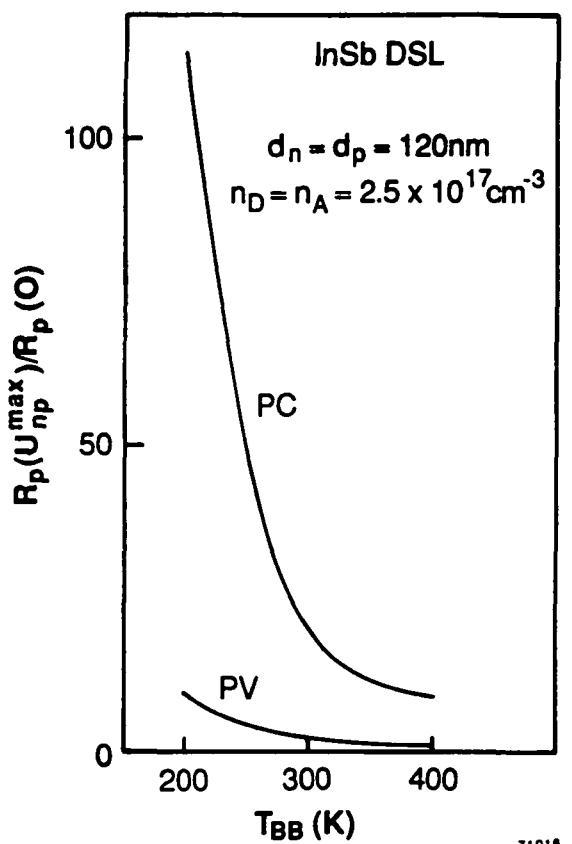
Spectrally Agile nipi Detector

incident spectrum: $\phi_0 M_p(E, T_T)$

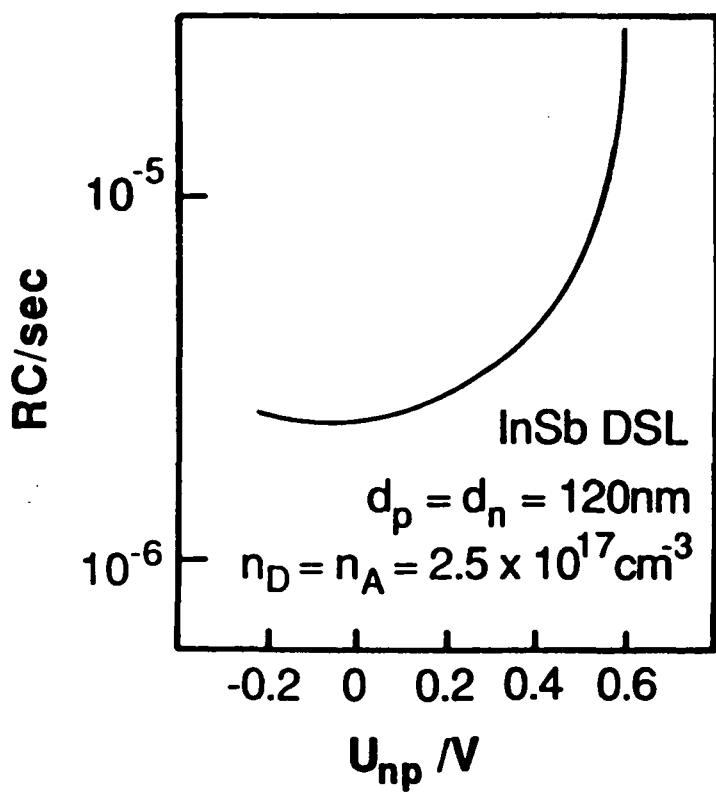
$$I_{ph}(U_{np}) = \frac{q\mu\tau(U_{np})V_a}{L} \phi_0 \int dE \eta(U_{np}, E) M_p(E, T_T)$$

$$= \frac{q\mu\tau(U_{np})V_a}{L} \phi_0 \bar{\eta}(U_{np}, T_T)$$

$$\frac{I_{ph}(U_{np1})}{I_{ph}(U_{np2})} = \frac{\tau(U_{np1})}{\tau(U_{np2})} \frac{\bar{\eta}(U_{np1}, T_T)}{\bar{\eta}(U_{np2}, T_T)} \rightarrow T_T$$



71016

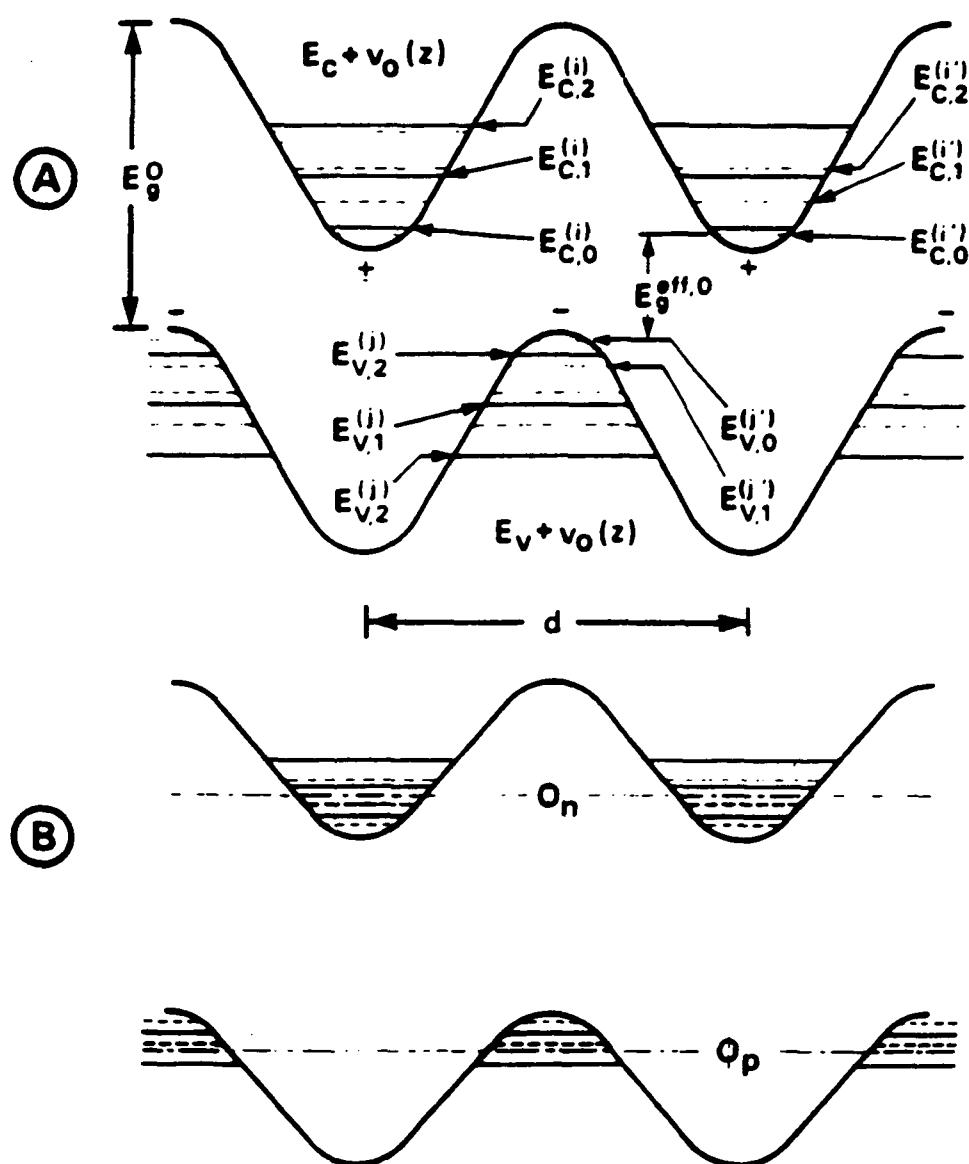


71017

Schematic Band Diagram for Doping Superlattice

A: Ground state

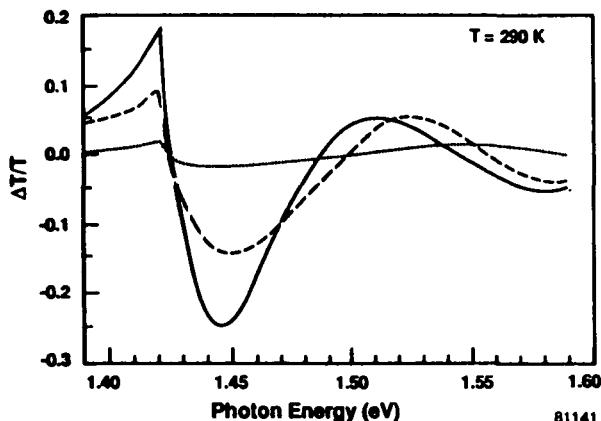
B: Excited state



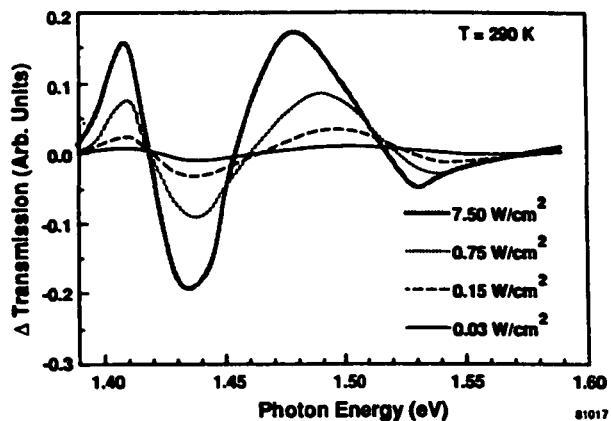
DIRECTION OF PERIODICITY z

Comparison of Theoretical and Experimental Results for Doping SL Transmission Nonlinearity

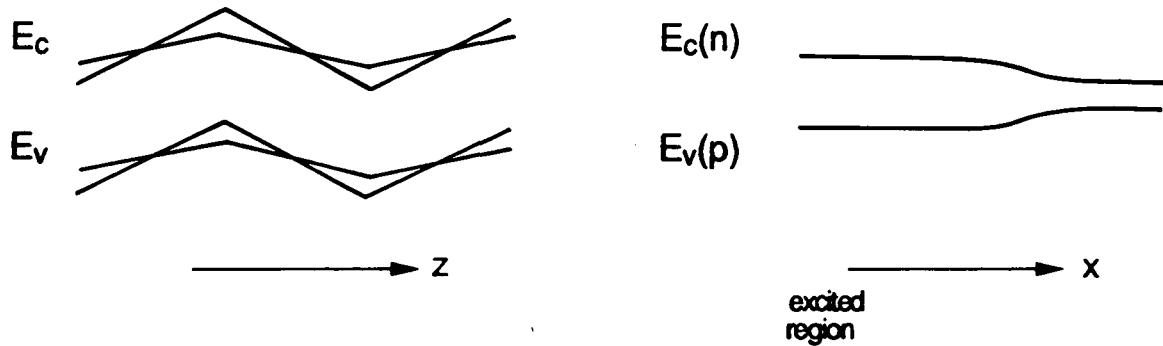
Theoretical Calculation of Optically Modulated Transmission
(GaAs Doping SL for Different Excitation Levels)



Optically Modulated Transmission
(GaAs Doping SL for Different Excitation Levels)



Lateral Charge Carrier Distribution

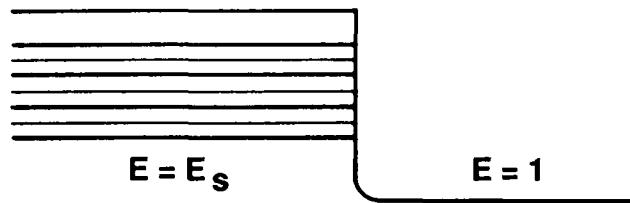


$$j_n \propto [(V(n^{(2)}) - V_0) + kT] (dn^{(2)}/dx)$$

$$R(n^{(2)}) \propto n^{(2)} p^{(2)} \exp(-V(n^{(2)})/kT)$$

$$n^{(2)}(x) \approx n_0^{(2)} \exp(-x/L(n^{(2)}))$$

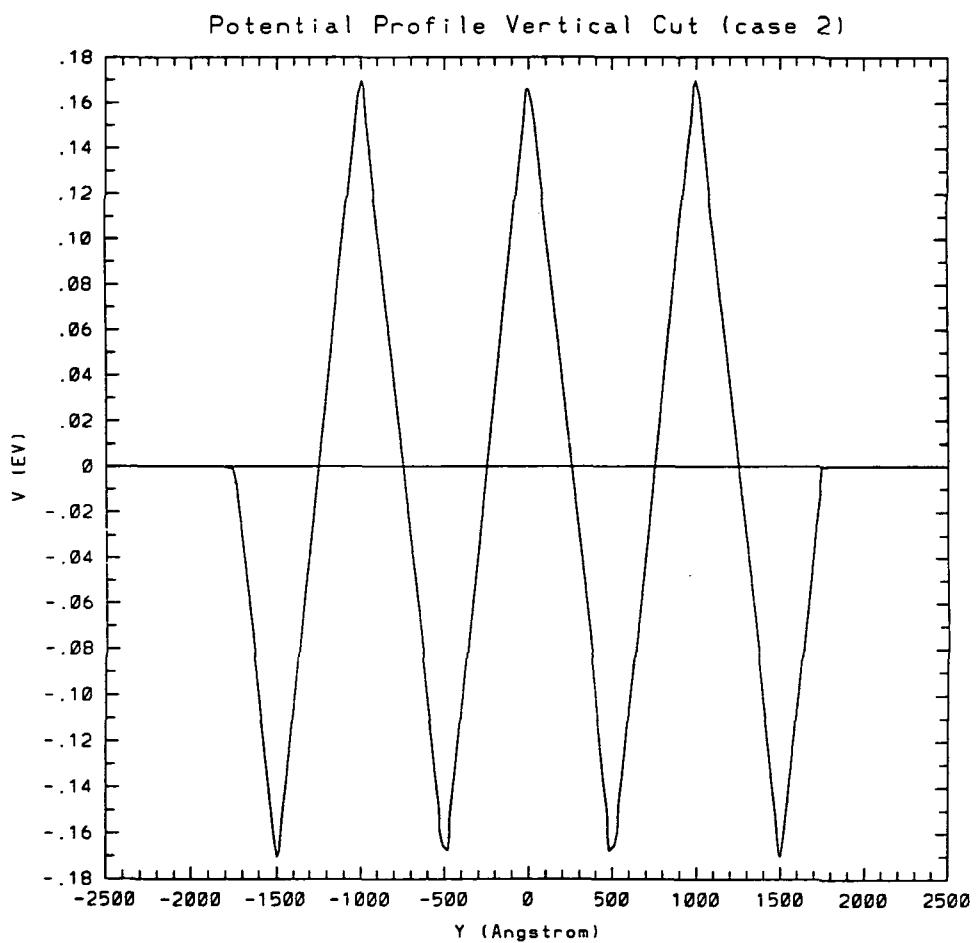
Potential At Surface

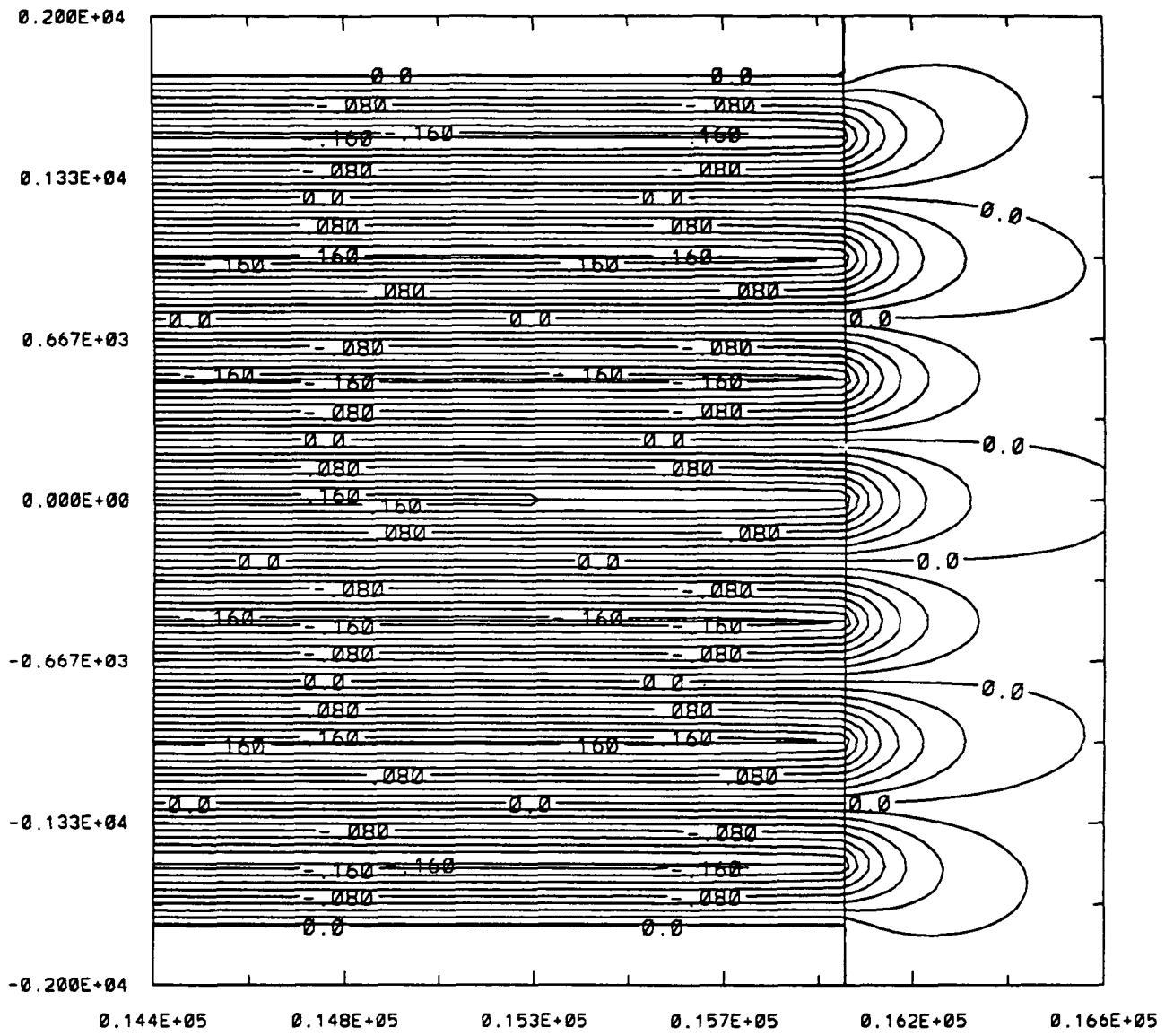


**Surface Recombination May Reduce Effective Lifetime
→ Reduce Photoconductive Gain**

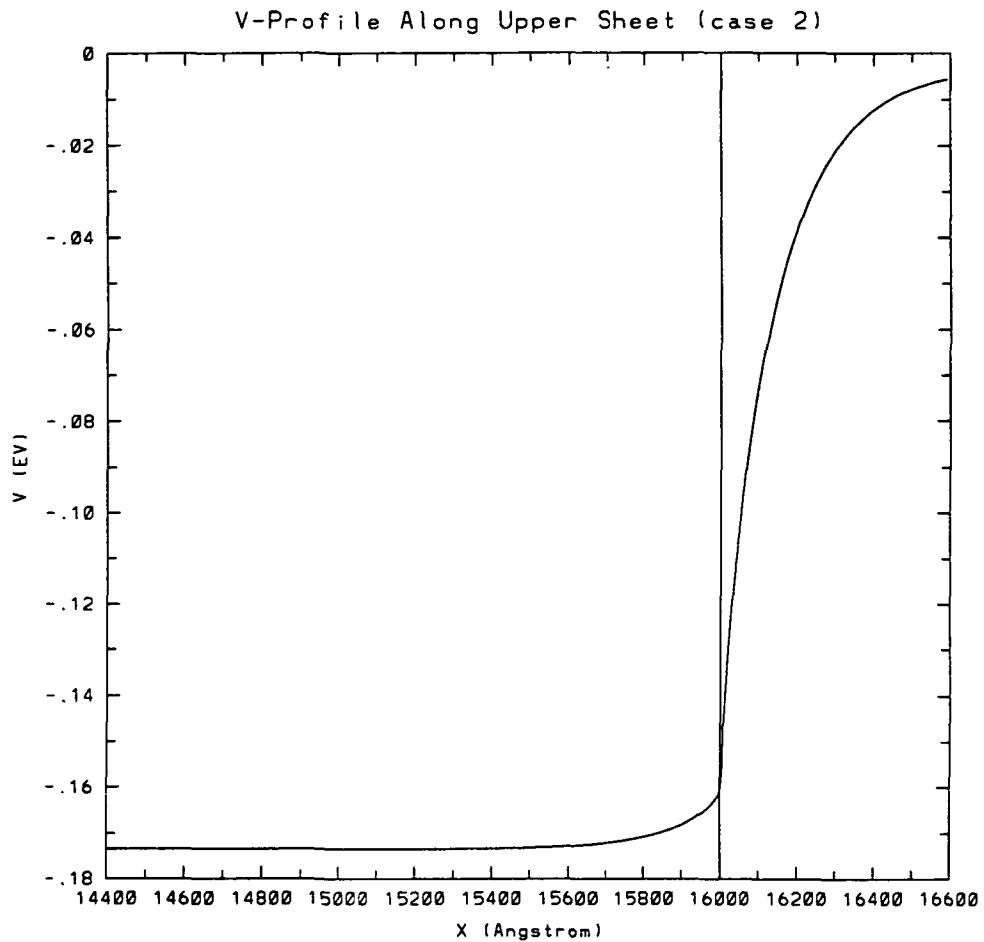
Surface Potential Barrier

$$\sigma V_s \sim \frac{2V_0}{2E_s}$$





ORIGINAL PAGE IS
OF POOR QUALITY



Summary

- IR detection with nipi SL based on InAs or InSb is feasible.
- Detector performance can be competitive.
- Spectrally agile detectors may be practical.
- Non-uniform excitation, surface and contact effects are critical.
- Optical nonlinearity can be useful.